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release of a sacrificial layer a free portion moves out of the plane of the substrate in a self-assembling manner. A sensor is formed on the same substrate, and includes an active layer and contacts. The active layer may be substantially transparent to light at infrared wavelengths. The micro-spring interconnects and the sensor are integrated on the substrate and configured using a compatible manufacturing process.

Please substitute the following amended paragraph for the first full paragraph on page 6:

Spring contacts 20 and 22 are photolithographically patterned on substrate 18 and designed for electrical connections between devices. An inherent stress gradient in each spring contact causes—free portions of the spring contacts to bend up and away from the substrate when a sacrificial layer is selectively removed. An anchor portion remains fixed to the substrate. The spring contact is made of an elastic material and the free portions, which are initially fixed, before the sacrificial layer is selectively removed from the substrate, provides for compliant contacts between devices for an electrical interconnection.

Please substitute the following amended paragraph for the fourth full paragraph on page 8:

Cux By

Turning to stage 2, illustrated by FIGURES 5b and 6b, a hydrogenated amorphous silicon sensor (a-Si:H) component or 44 is top of active layer grown on transparent/conductive layer 42, a-Si:H sensor component 44 is usually comprised of three layers. The first layer 44a, is a n⁺doped layer of material, typically less than 1,000 angstroms in Though not limited thereto, the first layer 44a may be a n⁺ phosphorous-doped amorphous silicon, or n⁺ arsenic-doped silicon. A second layer 44b is intrinsic amorphous silicon, of a thickness less than a micron, preferably in the range of 3,000-5,000 angstroms. The third layer 44c of sensor element 44 is a p*-doped amorphous silicon of approximately 100 angstroms thickness. An example of a p*-doped amorphous silicon which may